



NVLAP LAB CODE 200707-0



ETSI EN 301 489-1 V1.6.1 (2005-09)
ETSI EN 301 489-6 V1.2.1 (2002-08)

MEASUREMENT AND TEST REPORT

For

Shenzhen Guo Wei Electronics Co. Ltd.

No.68 Guo Wei Road, Liantang Industrial District, Shenzhen, Guangdong, P.R.C

Model: DECT72-C22 TAM

This Report Concerns: <input checked="" type="checkbox"/> Original Report		Equipment Type: DECT Cordless Phone
Test Engineer:	Karo Liao	
Report Number:	RSZ08060403-2 base	
Test Date:	2008-06-12 to 2008-06-20	
Report Date:	2008-06-24	
Reviewed By:	EMC Manager: Green Xu <i>Green Xu</i>	
Prepared By:	Bay Area Compliance Laboratories Corp. (Shenzhen) 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone, Shenzhen, Guangdong, China Tel: +86-755-33320018 Fax: +86-755-33320008	

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TABLE OF CONTENTS

GENERAL INFORMATION.....	4
PRODUCT DESCRIPTION FOR EQUIPMENT UNDER TEST (EUT)	4
OBJECTIVE	4
RELATED SUBMITTAL(S)/GRANT(S).....	4
TEST METHODOLOGY	4
TEST FACILITY	4
SYSTEM TEST CONFIGURATION.....	6
DESCRIPTION OF TEST CONFIGURATION	6
EQUIPMENT MODIFICATIONS	6
EXTERNAL I/O CABLE.....	6
CONFIGURATION OF TEST SETUP	7
BLOCK DIAGRAM OF TEST SETUP	7
SUMMARY OF TEST RESULTS.....	8
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - CONDUCTED EMISSIONS.....	9
MEASUREMENT UNCERTAINTY	9
EUT SETUP	9
EMI TEST RECEIVER SETUP.....	10
TEST EQUIPMENT LIST AND DETAILS.....	10
TEST PROCEDURE	10
TEST RESULTS SUMMARY	10
TEST DATA	11
PLOT(S) OF TEST DATA.....	12
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - RADIATED EMISSIONS	16
MEASUREMENT UNCERTAINTY	16
TEST SYSTEM SETUP	16
EMI TEST RECEIVER SETUP.....	17
TEST EQUIPMENT LIST AND DETAILS.....	17
TEST PROCEDURE	17
CORRECTED AMPLITUDE & MARGIN CALCULATION	17
TEST RESULTS SUMMARY	17
TEST DATA	18
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - HARMONIC CURRENT EMISSIONS.....	19
TEST EQUIPMENT	19
TEST SYSTEM SETUP	19
TEST STANDARD.....	19
TEST DATA AND SETUP PHOTO.....	19
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - VOLTAGE FLUCTUATION AND FLICKER.....	24
TEST EQUIPMENT	24
TEST SYSTEM SETUP	24
TEST STANDARD	24
TEST DATA AND SETUP PHOTO.....	24
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2- ELECTROSTATIC DISCHARGE	26
TEST EQUIPMENT	26
TEST SYSTEM SETUP	26
TEST STANDARD	26

TEST PROCEDURE	27
TEST DATA AND SETUP PHOTO.....	27
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - RF ELECTROMAGNETIC FIELD (80 MHz to 1000 MHz) AND (1400 MHz to 2000 MHz)	30
TEST EQUIPMENT	30
TEST SYSTEM SETUP	30
TEST STANDARD	31
TEST PROCEDURE	31
TEST DATA AND SETUP PHOTO.....	32
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - FAST TRANSIENT IMMUNITY COMMON MODE	33
TEST EQUIPMENT	33
TEST SYSTEM SETUP	33
TEST STANDARD	33
TEST PROCEDURE	33
TEST DATA AND SETUP PHOTO.....	34
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - SURGES, COMMON AND DIFFERENTIAL MODE	36
TEST EQUIPMENT	36
TEST SYSTEM SETUP	36
TEST STANDARD	36
TEST PROCEDURE	37
TEST DATA AND SETUP PHOTO.....	37
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - RF COMMON MODE, 0.15 MHz to 80 MHz)	39
TEST EQUIPMENT	39
TEST SETUP.....	39
TEST STANDARD	39
TEST PROCEDURE	40
TEST DATA AND SETUP PHOTO.....	40
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - VOLTAGE DIPS AND INTERRUPTIONS.....	42
TEST EQUIPMENT	42
TEST SYSTEM SETUP	42
TEST STANDARD	42
TEST PROCEDURE	42
TEST DATA AND SETUP PHOTO.....	43
EXHIBIT A - EUT PHOTOGRAPHS.....	44
FULL VIEW.....	44
EUT - TOP VIEW	44
EUT - BOTTOM VIEW	45
EUT - COVER OFF VIEW	45
EUT - MAIN BOARD TOP COMPONENTS VIEW.....	46
EUT - MAIN BOARD BOTTOM COMPONENTS VIEW	46
EUT - KEY BOARD TOP COMPONENTS VIEW.....	47
EUT - KEY BOARD BOTTOM COMPONENTS VIEW	47
EUT - SIM CARD BOARD TOP COMPONENTS VIEW	48
EUT - SIM CARD BOARD BOTTOM COMPONENTS VIEW	48
AC/DC ADAPTER VIEW	49
EXHIBIT B – TEST SETUP PHOTOGRAPHS.....	50
CONDUCTED EMISSIONS - FRONT VIEW (AC PORT).....	50
CONDUCTED EMISSIONS - SIDE VIEW (AC PORT)	50
CONDUCTED EMISSIONS - FRONT VIEW (RJ11 PORT)	51
CONDUCTED EMISSIONS - SIDE VIEW (RJ11 PORT)	51
RADIATED EMISSIONS - FRONT VIEW	52
RADIATED EMISSIONS - REAR VIEW	52

GENERAL INFORMATION

Product Description for Equipment under Test (EUT)

The *Shenzhen Guo Wei Electronics Co. Ltd.*'s product, model number: *DECT72-C22 TAM* or the "EUT" as referred to in this report is a *DECT Cordless Phone*, which measures approximately: 16.0 cm L x 11.4 cm W x 4.2 cm H, rated input voltage: DC 7.5V Adapter.

Adapter Information:

Model: SW-075030BS;

Input: 100-240VAC 50/60Hz 0.2A Max;

Output: 7.5V/300mA

** All measurement and test data in this report was gathered from production sample serial number: 0806009 (Assigned by BACL, Shenzhen). The EUT was received on 2008-06-04.*

Objective

The following test report is prepared on behalf of *Shenzhen Guo Wei Electronics Co. Ltd.* in accordance with ETSI EN 301 489-1 V1.6.1 (2005-09) Plus Provisions of ETSI EN 301 489-6 V1.2.1 (2002-08), Electromagnetic compatibility and Radio spectrum Matters (ERM); ElectroMagnetic Compatibility (EMC) standard for radio equipment and services; Part 6: Specific conditions for Digital Enhanced Cordless Telecommunications (DECT) equipment.

The objective of the manufacturer is to determine compliance with ETSI EN 301 489-1 V1.6.1 (2005-09) Plus Provisions of ETSI EN 301 489-6 V1.2.1 (2002-08).

Related Submittal(s)/Grant(s)

No related submittal(s).

Test Methodology

All measurements contained in this report were conducted with ETSI EN 301 489-1 V1.6.1 (2005-09).

Test Facility

The Test site used by Bay Area Compliance Laboratories Corp.(Shenzhen) to collect test data is located in the 6/F, the 3rd Phase of WanLi Industrial Building, ShiHua Road, FuTian Free Trade Zone Shenzhen, Guangdong, China.

Test site at Bay Area Compliance Laboratories Corp. (Shenzhen) has been fully described in reports submitted to the Federal Communication Commission (FCC). The details of these reports have been found to be in compliance with the requirements of Section 2.948 of the FCC Rules on November 04, 2004. The facility also complies with the radiated and AC line conducted test site criteria set forth in ANSI C63.4-2003.

The Federal Communications Commission has the reports on file and is listed under FCC Registration No.: 382179. The test site has been approved by the FCC for public use and is listed in the FCC Public Access Link (PAL) database.

Additionally, Bay Area Compliance Laboratories Corp. (Shenzhen) is a National Institute of Standards and Technology (NIST) accredited laboratory, under the National Voluntary Laboratory Accredited Program (Lab Code 200707-0).



NVLAP LAB CODE 200707-0

The current scope of accreditations can be found at
<http://ts.nist.gov/Standards/scopes/2007070.htm>

SYSTEM TEST CONFIGURATION

Description of Test Configuration

The system was configured for testing in a typical fashion (as normally used by a typical user).

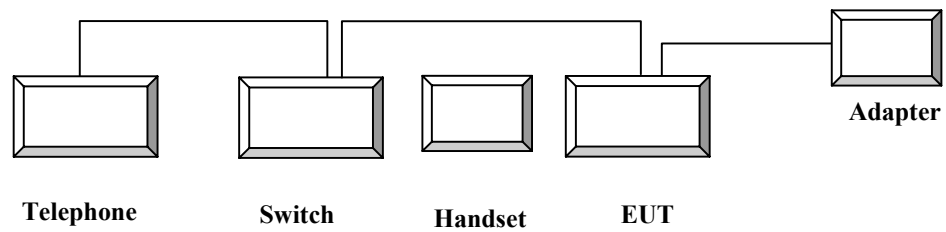
Equipment Modifications

No modifications were made to the unit tested.

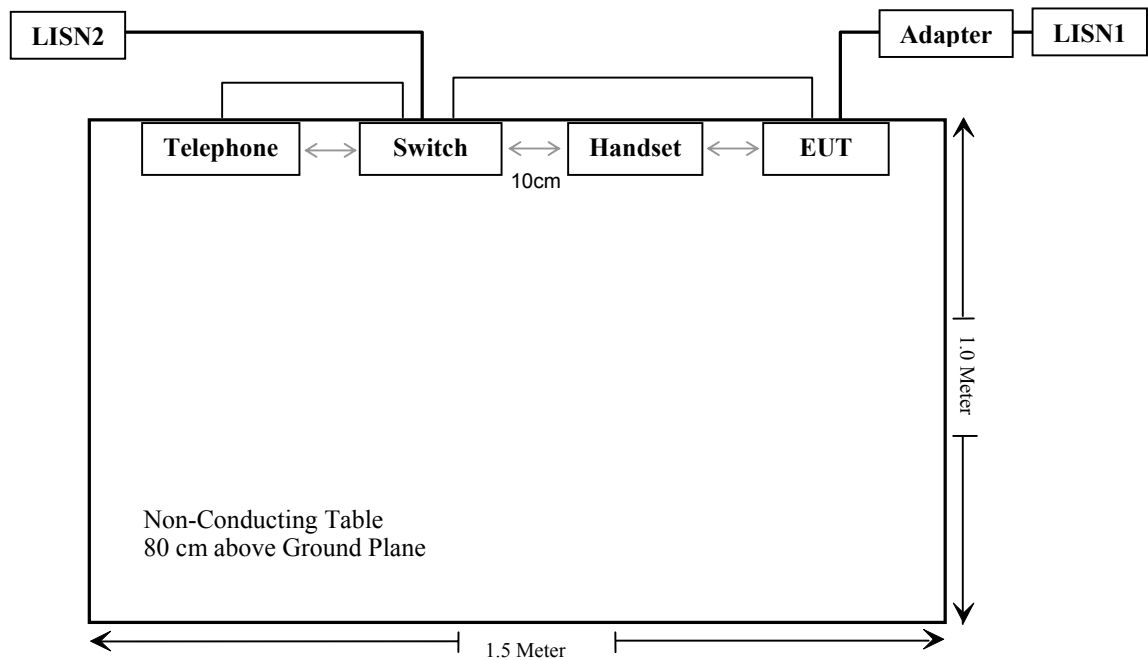
External I/O Cable

Cable Description	Length (M)	From/Port	To
Unshielded Detachable Telephone Cable	3.04	EUT	PSTN
Unshielded Undetachable Power Cable	2.03	Adapter	EUT

Configuration of Test Setup



Block Diagram of Test Setup



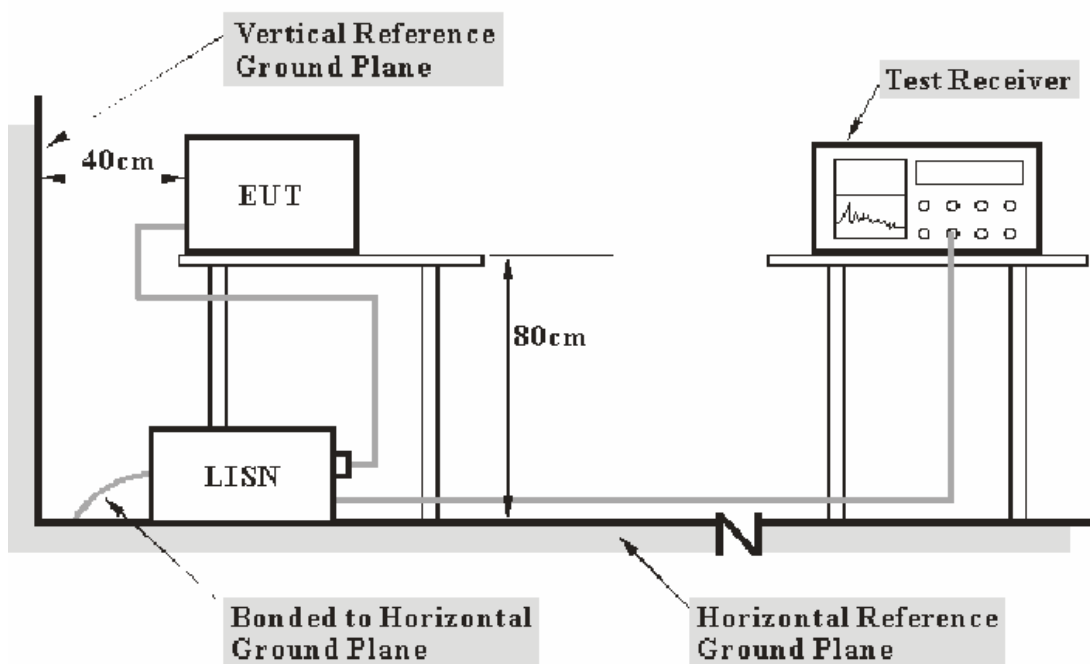
SUMMARY OF TEST RESULTS

ETSI EN 301 489-6 V1.2.1 (2002-08)	Description of Test	Result
§7.1	Reference to clauses EN 301 489-1 §8.4 AC mains power input/output ports	Compliant
	Reference to clauses EN 301 489-1 §8.3 DC power input/output ports	N/A
	Reference to clauses EN 301 489-1 §8.2 Enclosure of ancillary equipment measured on a stand alone basis	Compliant
	Reference to clauses EN 301 489-1 §8.5 Harmonic current emissions (AC mains input port)	Compliant
	Reference to clauses EN 301 489-1 §8.6 Voltage fluctuations and flicker (AC mains input port)	Compliant
	Reference to clauses EN 301 489-1 §8.7 Telecommunication ports	Compliant
§7.2	Reference to clauses EN 301 489-1 §9.2 Radio frequency electromagnetic field (80 MHz to 1 000 MHz and 1 400 MHz to 2 000 MHz)(EN 61000-4-3)	Compliant
	Reference to clauses EN 301 489-1 §9.3 Electrostatic discharge (EN 61000-4-2)	Compliant
	Reference to clauses EN 301 489-1 §9.4 Fast transients, common mode (EN 61000-4-4)	Compliant
	Reference to clauses EN 301 489-1 §9.5 Radio frequency, common mode (EN 61000-4-6)	Compliant
	Reference to clauses EN 301 489-1 §9.6 Transients and surges in the vehicular environment (ISO 7637-2)	N/A
	Reference to clauses EN 301 489-1 §9.8 Surges (EN 61000-4-5)	Compliant
	Reference to clauses EN 301 489-1 §9.7 Voltage dips and interruptions (EN 61000-4-11)	Compliant

ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - CONDUCTED EMISSIONS**Measurement Uncertainty**

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, and LISN.

Based on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of any conducted emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is ± 2.4 dB.

EUT Setup

- Note:**
1. Support units were connected to second LISN.
 2. Both of LISNs (AMN) 80 cm from EUT and at the least 80 cm from other units and other metal planes support units.

The setup of EUT is according with per EN 301 489-1 measurement procedures. The specification used was with the EN 301 489-1 limits.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to 230V/50Hz power source.

EMI Test Receiver Setup

The EMI test receiver was set to investigate the spectrum from 150 kHz to 30 MHz.

During the conducted emission test, the EMI test receiver was set with the following configurations:

<i>Frequency Range</i>	<i>IFBW</i>
150 kHz – 30 MHz	9 kHz

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Com-Power	L.I.S.N.	LI-200	12005	N/A	N/A
Com-Power	L.I.S.N.	LI-200	12208	N/A	N/A
Rohde & Schwarz	EMI Test Receiver	ESCS30	DE25330	2008-03-25	2009-03-25
Rohde & Schwarz	L.I.S.N.	ESH2-Z5	892107/021	2008-03-25	2009-03-25
SCHAFFNER	CDN	CDN T200	16891	2007-10-16	2008-10-16

* Com-Power's LISN were used as the supporting equipment.

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

Test Procedure

During the conducted emission test, the adapter was connected to the outlet of the LISN.

Maximizing procedure was performed on the six (6) highest emissions of the EUT.

All data was recorded in the Quasi-peak and average detection mode.

Test Results Summary

According to the recorded data in following table, the EUT complied with the ETSI EN 301 489-1, with the worst margin reading of:

3.60 dB at 0.400 MHz in the **Line-1** conductor mode

15.30 dB at 10.750 MHz in the **RJ11 Port**

Test Data**Environmental Conditions**

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Karo Liao on 2008-06-18.

Test Mode: Talking (AC Port)

Line Conducted Emissions				EN 301 489-1/EN 55022	
Frequency (MHz)	Amplitude (dBμV)	Detector (QP/AV)	Conductor (Line-1/ Line-2)	Limit (dBμV)	Margin (dB)
0.400	54.30	QP	Line-1	57.90	3.60
2.545	51.30	QP	Line-1	56.00	4.70
0.650	50.50	QP	Line-1	56.00	5.50
1.460	49.80	QP	Line-1	56.00	6.20
2.460	46.50	QP	Line-2	56.00	9.50
0.400	37.30	AV	Line-1	47.90	10.60
2.535	33.60	AV	Line-1	46.00	12.40
17.915	37.40	QP	Line-2	50.00	12.60
0.645	33.20	AV	Line-1	46.00	12.80
0.390	45.20	QP	Line-2	58.10	12.90
0.655	41.70	QP	Line-2	56.00	14.30
1.450	31.00	AV	Line-1	46.00	15.00
7.320	44.90	QP	Line-1	60.00	15.10
13.890	44.30	QP	Line-1	60.00	15.70
17.915	33.20	AV	Line-2	50.00	16.80
6.435	42.90	QP	Line-2	60.00	17.10
2.505	25.70	AV	Line-2	46.00	20.30
0.390	27.20	AV	Line-2	48.10	20.90
10.750	29.10	AV	Line-2	50.00	20.90
10.750	38.30	QP	Line-2	60.00	21.70
0.655	24.00	AV	Line-2	46.00	22.00
7.285	25.90	AV	Line-1	50.00	24.10
6.440	24.70	AV	Line-2	50.00	25.30
13.765	24.60	AV	Line-1	50.00	25.40

Test Mode: Talking (RJ11 Port)

Line Conducted Emissions				EN 301 489-1/EN 55022	
Frequency (MHz)	Amplitude (dB μ V)	Detector (QP/AV)	Test Port	Limit (dB μ V)	Margin (dB)
10.750	48.70	AV	RJ11	64.00	15.30
10.750	50.70	QP	RJ11	74.00	23.30
3.580	39.50	AV	RJ11	64.00	24.50
2.150	47.40	QP	RJ11	74.00	26.60
17.920	35.60	AV	RJ11	64.00	28.40
3.580	44.90	QP	RJ11	74.00	29.10
2.150	34.10	AV	RJ11	64.00	29.90
1.230	43.30	QP	RJ11	74.00	30.70
1.230	30.00	AV	RJ11	64.00	34.00
17.92	36.20	QP	RJ11	74.00	37.80
0.710	31.10	QP	RJ11	74.00	42.90
0.710	13.00	AV	RJ11	64.00	51.00

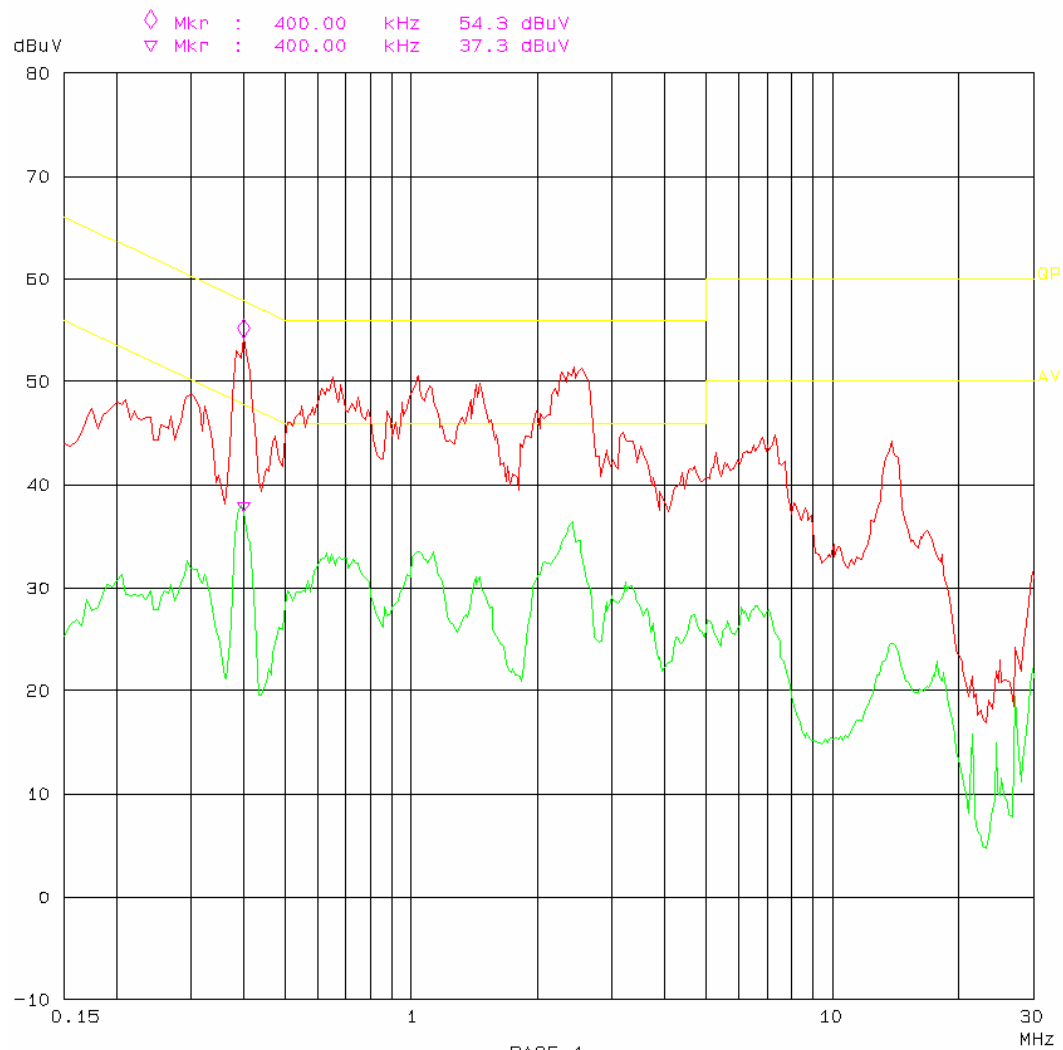
Plot(s) of Test Data

Plot(s) of Test Data is presented hereinafter as reference.

Conduction Emission
EN301489-6

18. Jun 08 10:22

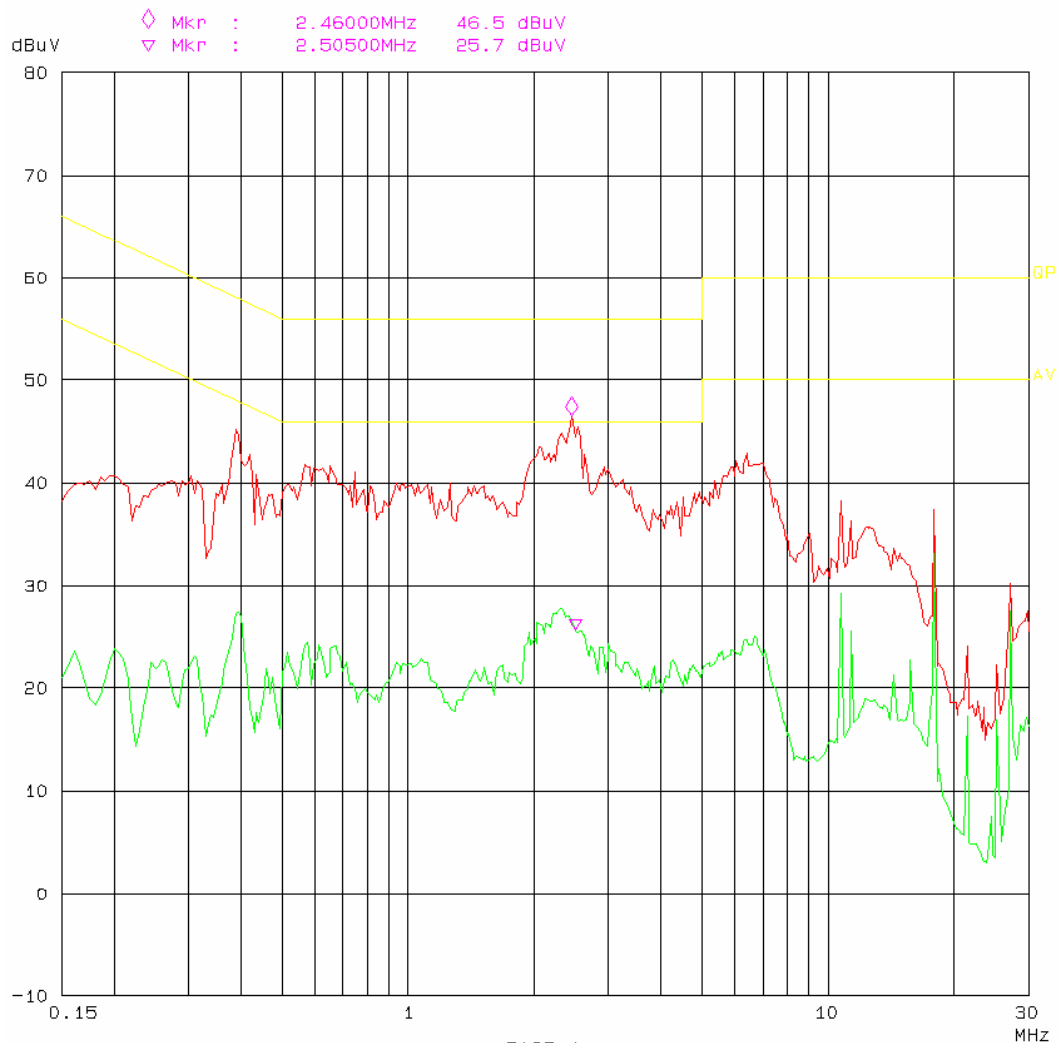
EUT: DECT CORDLESS PHONE M/N: DECT72-C22 TAM
Manuf: Guo Wei
Op Cond: Talking
Operator: Bruce
Test Spec: AC 230V/50Hz Line-1
Comment: Temp: 25 Hum: 56%



Conduction Emission
EN301489-6

18. Jun 08 10:54

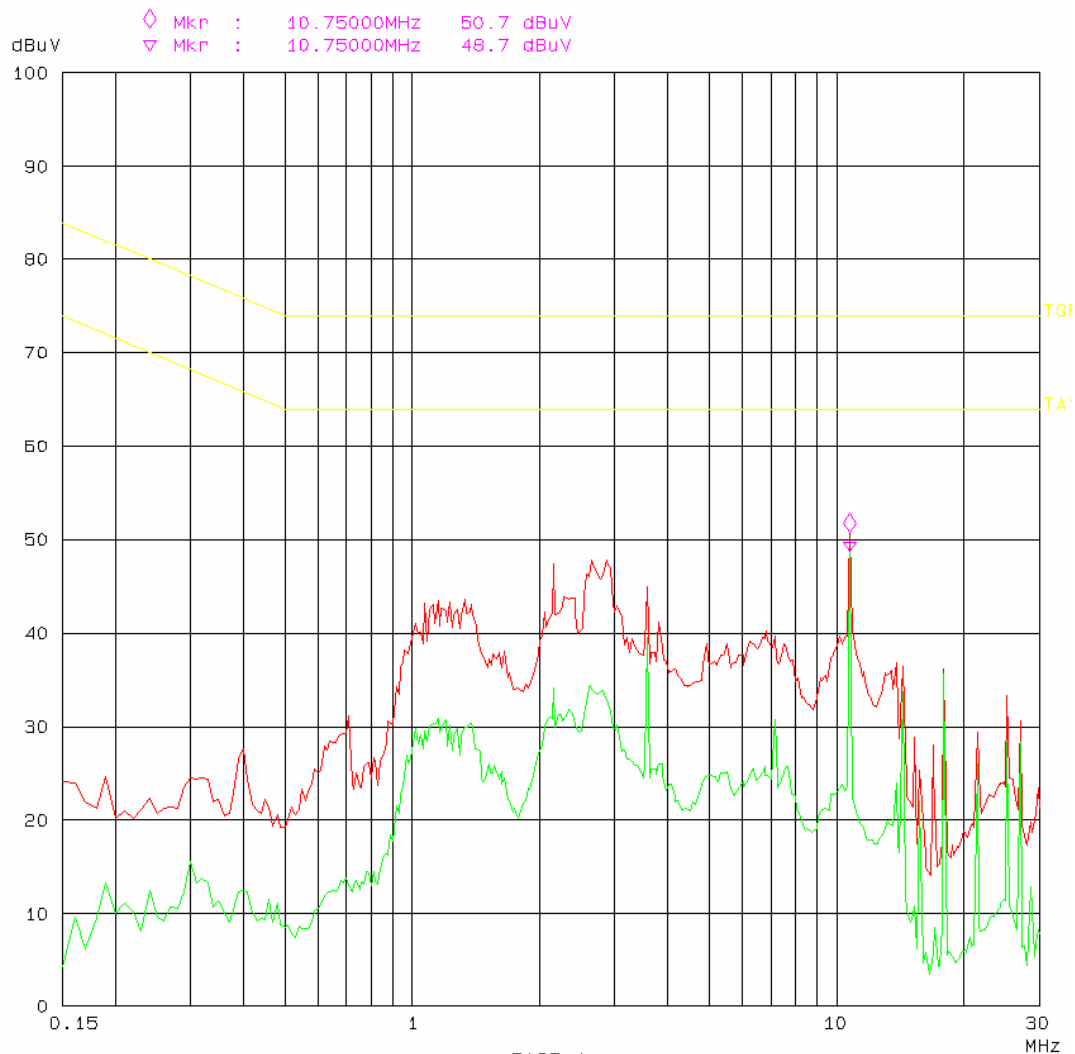
EUT: DECT CORDLESS PHONE M/N: DECT72-C22 TAM
Manuf: Guo Wei
Op Cond: Talking
Operator: Bruce
Test Spec: AC 230V/50Hz Line-2
Comment: Temp: 25 Hum: 56%



Conduction Emission
EN301489-6

18. Jun 08 11:27

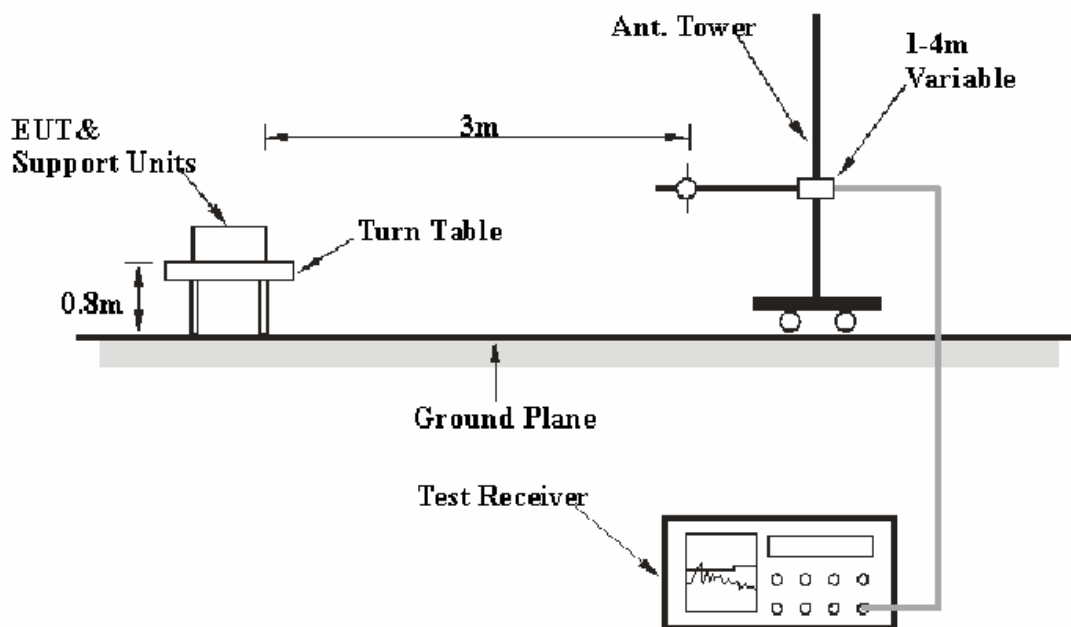
EUT: DECT CORDLESS PHONE M/N: DECT72-C22 TAM
Manuf: Guo Wei
Op Cond: Talking
Operator: Bruce
Test Spec: AC 230V/50Hz RJ11
Comment: Temp: 25 Hum: 56%



ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - RADIATED EMISSIONS**Measurement Uncertainty**

All measurements involve certain levels of uncertainties, especially in field of EMC. The factors contributing to uncertainties are spectrum analyzer, cable loss, antenna factor calibration, antenna directivity, antenna factor variation with height, antenna phase center variation, antenna factor frequency interpolation, measurement distance variation, site imperfections, mismatch (average), and system repeatability.

Based on NIS 81, The Treatment of Uncertainty in EMC Measurements, the best estimate of the uncertainty of a radiation emissions measurement at Bay Area Compliance Laboratories Corp. (Shenzhen) is ± 4.0 dB.

Test System Setup

The radiated emission tests were performed in the 3 meters chamber B, using the setup accordance with the EN 301 489-1. The specification used was the EN 301 489-1.

The external I/O cables were draped along the test table and formed a bundle 30 to 40 cm long in the middle.

The spacing between the peripherals was 10 cm.

The adapter was connected to a 230 VAC/50 Hz power source.

EMI Test Receiver Setup

The system was investigated from 30 MHz to 1000 MHz.

During the radiated emission test, the EMI test receiver Setup was set with the following configurations:

<i>Frequency Range</i>	<i>RBW</i>	<i>VBW</i>	<i>IFBW</i>
30 MHz – 1000 MHz	100 kHz	300 kHz	120 kHz

Test Equipment List and Details

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
HP	Amplifier	HP8447D	2944A09795	2007-11-15	2008-11-15
Rohde & Schwarz	EMI Test Receiver	ESCI	100035	2007-10-16	2008-10-16
Sunol Sciences	Broadband Antenna	JB1	A040904-1	2007-08-14	2008-08-14

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

Test Procedure

For the radiated emissions test, the adapter was connected to the AC floor outlet.

Maximizing procedure was performed on the highest emissions to ensure that the EUT complied with all installation combinations.

All data was recorded in the PK detection mode.

Corrected Amplitude & Margin Calculation

The Corrected Amplitude is calculated by adding the Antenna Factor and Cable Loss, and subtracting the Amplifier Gain from the Meter Reading. The basic equation is as follows:

$$\text{Corrected Amplitude} = \text{Meter Reading} + \text{Antenna Factor} + \text{Cable Loss} - \text{Amplifier Gain}$$

The “**Margin**” column of the following data tables indicates the degree of compliance with the applicable limit. For example, a margin of 7dB means the emission is 7dB below the limit for Class B. The equation for margin calculation is as follows:

$$\text{Margin} = \text{Limit} - \text{Corrected Amplitude}$$

Test Results Summary

According to the recorded data in following table, the EUT complied with the ETSI EN 301 489-1, with the worst margin reading of:

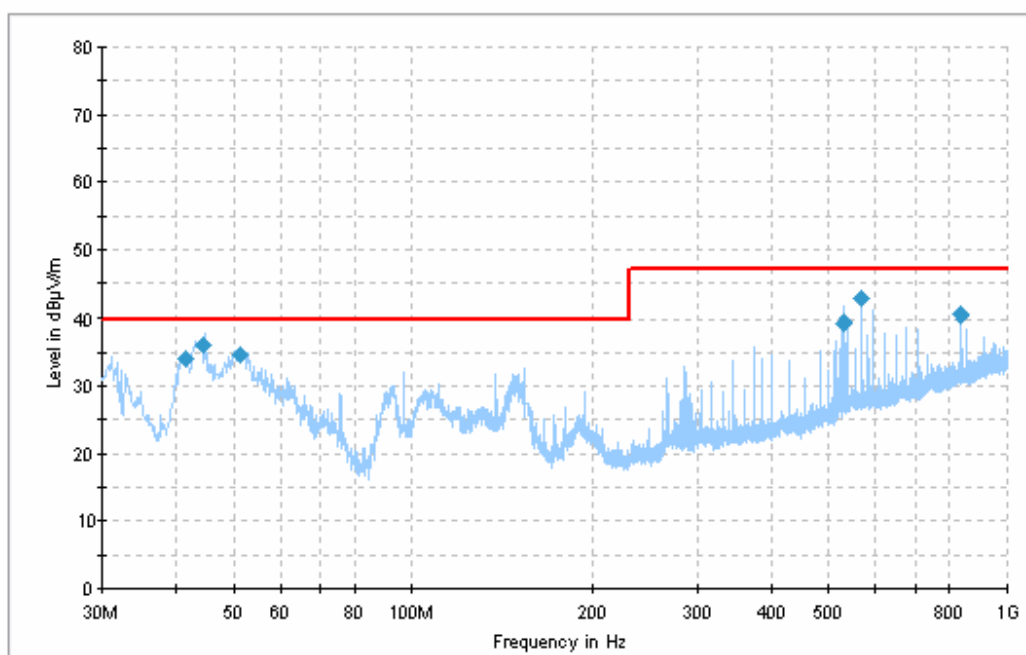
3.8 dB at 44.600500 MHz in the Vertical polarization

Test Data**Environmental Conditions**

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Bruce Zhang on 2008-06-17.

Test Mode: Talking



Frequency (MHz)	Corrected Amplitude (dBμV/m)	Antenna Height (cm)	Ant. Polarity (H/V)	Turntable Position (deg)	Correction Factor (dB)	Limit (dBμV/m)	Margin (dB)
44.600500	36.2	102.0	V	124.0	-14.5	40.0	3.8*
566.763438	42.8	102.0	V	93.0	-3.8	47.0	4.2
51.298375	34.8	102.0	V	194.0	-17.2	40.0	5.2
41.465250	34.1	119.0	V	240.0	-12.3	40.0	5.9
834.463562	40.4	259.0	V	0.0	0.2	47.0	6.6
530.464875	39.3	297.0	V	0.0	-4.6	47.0	7.7

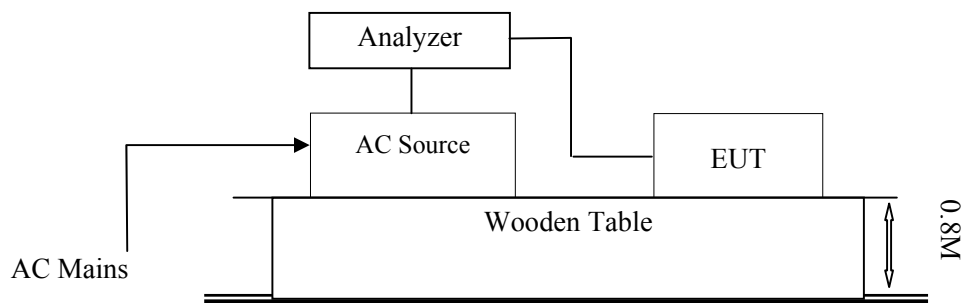
* Within measurement uncertainty.

ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - HARMONIC CURRENT EMISSIONS

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Harmonic/Flicker Analyzer	DPA500	303278	2008-03-25	2009-03-25
EM Test	AC Source	ACS500	303276	2008-03-25	2009-03-25

Test System Setup



Test Standard

ETSI EN 301 489-1 V1.6.1/EN 61000-3-2: 2006

Test Data and Setup Photo

Date of test:	14:17 2008-06-12
Measurement file name:	Harmonics_3_2_A14.rsd
Tester:	Bruce Zhang
Standard used:	EN 61000-3-2 Equipment Class A
Observation time:	150s
Customer:	Shenzhen Guo Wei Electronics Co. Ltd.
E. U. T.:	DECT Cordless Phone
Model:	DECT72-C22 TAM
Test Mode:	Talking

Average harmonic current results

Hn	I _{eff} [A]	I _{eff} [%]	Limit [A]	Result
1	6.204E-3	100.000		
2	165.247E-6	2.664	1.08	PASS
3	6.028E-3	97.172	2.30	PASS
4	241.453E-6	3.892	430.00E-3	PASS
5	5.881E-3	94.799	1.14	PASS
6	176.889E-6	2.851	300.00E-3	PASS
7	5.709E-3	92.029	770.00E-3	PASS
8	163.586E-6	2.637	230.00E-3	PASS
9	5.460E-3	88.015	400.00E-3	PASS
10	153.783E-6	2.479	184.00E-3	PASS
11	5.190E-3	83.655	330.00E-3	PASS
12	135.364E-6	2.182	153.33E-3	PASS
13	4.869E-3	78.490	210.00E-3	PASS
14	171.165E-6	2.759	131.43E-3	PASS
15	4.517E-3	72.804	150.00E-3	PASS
16	115.734E-6	1.866	115.00E-3	PASS
17	4.122E-3	66.451	132.35E-3	PASS
18	128.915E-6	2.078	102.22E-3	PASS
19	3.735E-3	60.199	118.42E-3	PASS
20	125.002E-6	2.015	92.00E-3	PASS
21	3.334E-3	53.740	160.71E-3	PASS
22	162.787E-6	2.624	83.64E-3	PASS
23	2.938E-3	47.352	146.74E-3	PASS
24	163.021E-6	2.628	76.66E-3	PASS
25	2.522E-3	40.651	135.00E-3	PASS
26	126.183E-6	2.034	70.77E-3	PASS
27	2.133E-3	34.387	124.99E-3	PASS
28	136.126E-6	2.194	65.71E-3	PASS
29	1.787E-3	28.798	116.39E-3	PASS
30	124.321E-6	2.004	61.33E-3	PASS
31	1.449E-3	23.358	108.87E-3	PASS
32	157.818E-6	2.544	57.50E-3	PASS
33	1.139E-3	18.354	102.27E-3	PASS
34	122.532E-6	1.975	54.12E-3	PASS
35	885.357E-6	14.271	96.44E-3	PASS
36	129.173E-6	2.082	51.11E-3	PASS
37	670.948E-6	10.815	91.21E-3	PASS
38	119.159E-6	1.921	48.42E-3	PASS
39	521.503E-6	8.406	86.53E-3	PASS
40	112.436E-6	1.812	46.00E-3	PASS

Maximum harmonic current results

Hn	leff [A]	leff [%]	Limit [A]	Result
1	6.742E-3	100.000		
2	280.985E-6	4.168	1.62	PASS
3	6.329E-3	93.882	3.45	PASS
4	370.389E-6	5.494	645.00E-3	PASS
5	6.077E-3	90.140	1.71	PASS
6	371.342E-6	5.508	450.00E-3	PASS
7	5.922E-3	87.838	1.15	PASS
8	310.328E-6	4.603	345.00E-3	PASS
9	5.615E-3	83.292	600.00E-3	PASS
10	296.054E-6	4.391	276.00E-3	PASS
11	5.353E-3	79.404	495.00E-3	PASS
12	246.934E-6	3.663	229.99E-3	PASS
13	5.021E-3	74.481	315.00E-3	PASS
14	279.577E-6	4.147	197.15E-3	PASS
15	4.645E-3	68.898	225.00E-3	PASS
16	219.898E-6	3.262	172.50E-3	PASS
17	4.245E-3	62.970	198.52E-3	PASS
18	252.691E-6	3.748	153.33E-3	PASS
19	3.851E-3	57.123	177.63E-3	PASS
20	239.196E-6	3.548	138.00E-3	PASS
21	3.466E-3	51.412	160.71E-3	PASS
22	247.728E-6	3.674	125.46E-3	PASS
23	3.618E-3	53.662	146.74E-3	PASS
24	307.790E-6	4.565	114.99E-3	PASS
25	2.652E-3	39.334	135.00E-3	PASS
26	263.449E-6	3.908	106.16E-3	PASS
27	2.257E-3	33.478	124.99E-3	PASS
28	219.753E-6	3.259	98.57E-3	PASS
29	1.892E-3	28.068	116.39E-3	PASS
30	240.033E-6	3.560	92.00E-3	PASS
31	1.570E-3	23.294	108.87E-3	PASS
32	266.389E-6	3.951	86.25E-3	PASS
33	1.266E-3	18.779	102.27E-3	PASS
34	212.112E-6	3.146	81.18E-3	PASS
35	971.140E-6	14.404	96.44E-3	PASS
36	196.289E-6	2.911	76.66E-3	PASS
37	763.253E-6	11.321	91.21E-3	PASS
38	280.310E-6	4.158	72.63E-3	PASS
39	612.771E-6	9.089	86.53E-3	PASS
40	233.551E-6	3.464	69.00E-3	PASS

Maximum harmonic voltage results

Hn	Ueff [V]	Ueff [%]	Limit [%]	Result
1	231.50	100.652		
2	77.76E-3	0.034	0.2	PASS
3	115.39E-3	0.050	0.9	PASS
4	13.23E-3	0.006	0.2	PASS
5	33.58E-3	0.015	0.4	PASS
6	13.42E-3	0.006	0.2	PASS
7	19.64E-3	0.009	0.3	PASS
8	12.82E-3	0.006	0.2	PASS
9	41.48E-3	0.018	0.2	PASS
10	12.45E-3	0.005	0.2	PASS
11	36.42E-3	0.016	0.1	PASS
12	13.99E-3	0.006	0.1	PASS
13	35.82E-3	0.016	0.1	PASS
14	12.54E-3	0.005	0.1	PASS
15	18.00E-3	0.008	0.1	PASS
16	12.44E-3	0.005	0.1	PASS
17	44.86E-3	0.020	0.1	PASS
18	14.89E-3	0.006	0.1	PASS
19	46.05E-3	0.020	0.1	PASS
20	15.82E-3	0.007	0.1	PASS
21	28.69E-3	0.012	0.1	PASS
22	13.51E-3	0.006	0.1	PASS
23	25.50E-3	0.011	0.1	PASS
24	13.56E-3	0.006	0.1	PASS
25	32.25E-3	0.014	0.1	PASS
26	14.49E-3	0.006	0.1	PASS
27	39.31E-3	0.017	0.1	PASS
28	17.21E-3	0.007	0.1	PASS
29	22.15E-3	0.010	0.1	PASS
30	14.31E-3	0.006	0.1	PASS
31	23.66E-3	0.010	0.1	PASS
32	12.30E-3	0.005	0.1	PASS
33	27.32E-3	0.012	0.1	PASS
34	13.14E-3	0.006	0.1	PASS
35	28.56E-3	0.012	0.1	PASS
36	15.40E-3	0.007	0.1	PASS
37	22.83E-3	0.010	0.1	PASS
38	13.87E-3	0.006	0.1	PASS
39	26.08E-3	0.011	0.1	PASS
40	12.13E-3	0.005	0.1	PASS



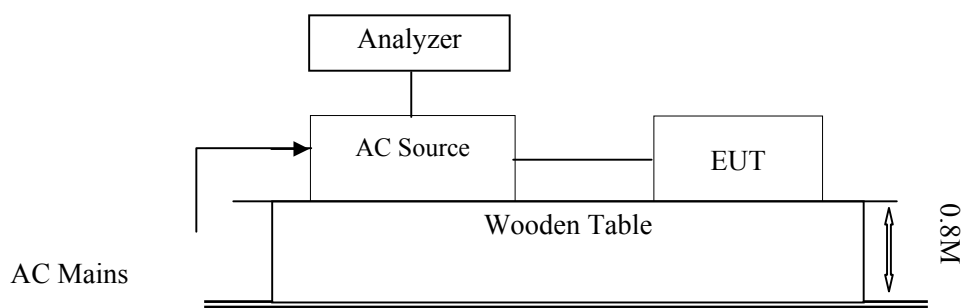
Test Set up Photo

ETSI EN 301 489-6 V1.2.1 (2002-08) §7.1 - VOLTAGE FLUCTUATION AND FLICKER

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Harmonic/Flicker Analyzer	DPA500	303278	2008-03-25	2009-03-25
EM Test	AC Source	ACS500	303276	2008-03-25	2009-03-25

Test System Setup



Test Standard

ETSI EN 301 489-1 V1.6.1/EN 61000-3-3: 1995+A1: 2001+A2: 2005

Test Data and Setup Photo

Date of test:	14:38 2008-06-18
Tester:	Bruce Zhang
Standard used:	EN 61000-3-3 Flicker
Short time (Pst):	10 min
Observation time:	10 min (1 Flicker measurement)
Flickermeter:	230V / 50Hz
Customer:	Shenzhen Guo Wei Electronics Co. Ltd.
E. U. T.:	DECT Cordless Phone
Model:	DECT72-C22 TAM
Test Mode:	Talking

Maximum Flicker results

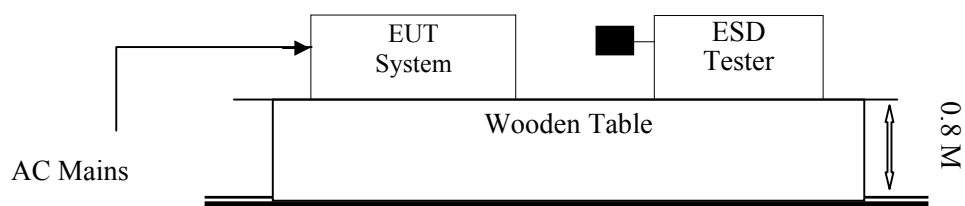
	EUT values	Limit	Result
Pst	0.028	1.00	PASS
Plt	0.028	0.65	PASS
dc [%]	0.004	3.30	PASS
dmax [%]	0.158	4.00	PASS
dt [s]	0.000	0.50	PASS



Test Set up Photo

ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2- ELECTROSTATIC DISCHARGE**Test Equipment**

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	ESD Tester	Dito	302105	2008-03-01	2009-03-01

Test System Setup

Remark: ■ is the tip of the electrode

EN 61000-4-2 specifies that a tabletop EUT shall be placed on a non-conducting table which is 80 centimeters above a ground reference plane and that floor mounted equipment shall be placed on a insulating support approximately 10 centimeters above a ground plane. During the tests, the EUT is positioned over a ground reference plane in conformance with this requirement.

For tabletop equipment, a 1.5 by 1.0-meter metal sheet (HCP) is placed on the table and connected to the ground plane via a metal strap with two 470 k Ohms resistors in series. The EUT and attached cables are isolated from this metal sheet by *0.5-millimeter* thick insulating material. A Vertical Coupling Plane (VCP) grounded on the ground plane through the same configuration as in the HCP is used.

Test Standard

ETSI EN 301 489-1 V1.6.1 / EN 61000-4-2: 1995+A1: 1998+A2: 2001

Test Level 3 for Air Discharge at ± 8 kV

Test Level 2 for Contact Discharge at ± 4 kV

Test Level

Level	Test Voltage Contact Discharge (\pm kV)	Test Voltage Air Discharge (\pm kV)
1.	2	2
2.	4	4
3.	6	8
4.	8	15
X.	Special	Special

Performance criterion: B

Test Procedure

Air Discharge:

This test is done on a non-conductive surface. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

Contact Discharge:

All the procedure shall be same as Section 8.3.1 of EN 61000-4-2, except that the tip of the discharge electrode shall touch the EUT before the discharge switch is operated.

Indirect discharge for horizontal coupling plane

At least 20 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT. The discharge electrode positions vertically at a distance of 0.1m from the EUT and with the discharge electrode touching the coupling plane.

Indirect discharge for vertical coupling plane

At least 20 single discharges shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Karo Liao on 2008-06-20.

Test Mode: Talking

Table 1: Electrostatic Discharge Immunity (Air Discharge)

EN 61000-4-2 Test Points		Test Levels									
		-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV	-15kV	+15kV
Surface	24 Points	A	A	A	A	A	A	A	A	/	/
Button Points	16	A	A	A	A	A	A	A	A	/	/
Slots	18 Points	A	A	A	A	A	A	A	A	/	/

Table 2: Electrostatic Discharge Immunity (Direct Contact)

EN 61000-4-2 Test Points		Test Levels									
		-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV	-15kV	+15kV
/		/	/	/	/	/	/	/	/	/	/

Table 3: Electrostatic Discharge Immunity (Indirect Contact HCP)

EN 61000-4-2 Test Points		Test Levels									
		-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV	-15kV	+15kV
Front Side		A	A	A	A	/	/	/	/	/	/
Back Side		A	A	A	A	/	/	/	/	/	/
Left Side		A	A	A	A	/	/	/	/	/	/
Right Side		A	A	A	A	/	/	/	/	/	/

Table 4: Electrostatic Discharge Immunity (Indirect Contact VCP)

EN 61000-4-2 Test Points		Test Levels									
		-2 kV	+2 kV	-4 kV	+4 kV	-6 kV	+6 kV	-8 kV	+8 kV	-15kV	+15kV
Front Side		A	A	A	A	/	/	/	/	/	/
Back Side		A	A	A	A	/	/	/	/	/	/
Left Side		A	A	A	A	/	/	/	/	/	/
Right Side		A	A	A	A	/	/	/	/	/	/

Air Discharge



Indirect Contact



Test Setup photos

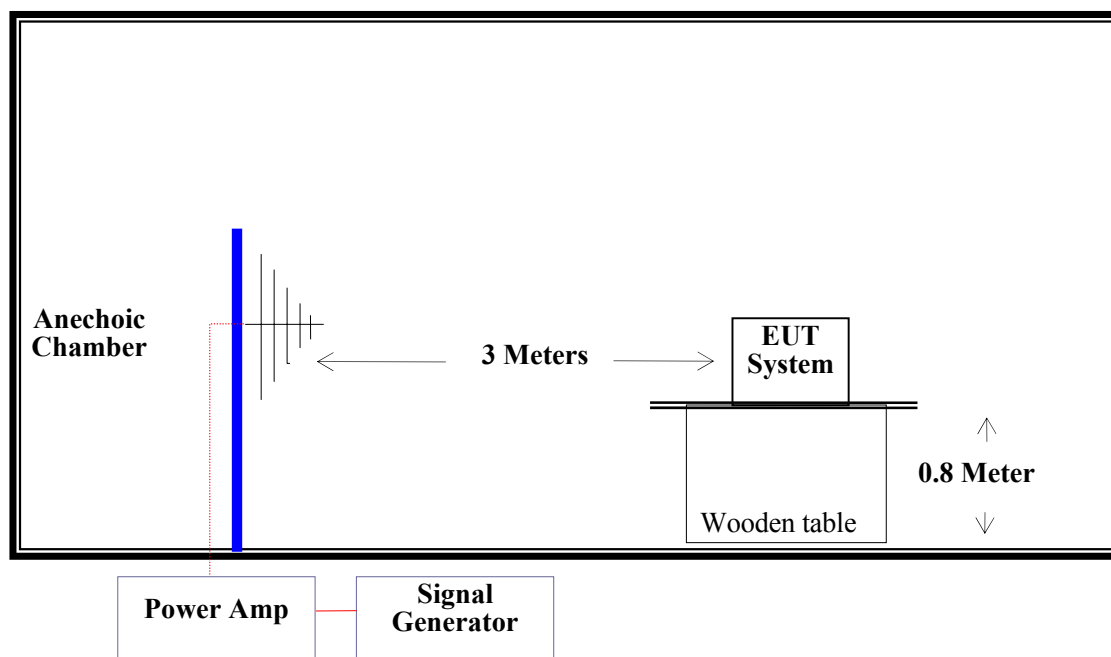
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - RF ELECTROMAGNETIC FIELD (80 MHz to 1000 MHz) AND (1400 MHz to 2000 MHz)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
Amplifier Research	Amplifier	150W1000	302657	2007-11-15	2008-11-15
Amplifier Research	Field Meter	FM5004	302149	2007-11-01	2008-11-01
Amplifier Research	Sensor	FP5000	301825	2008-02-22	2009-02-22
HP	Signal Generator	8648C	3426A01345	2007-10-10	2008-10-10
Sunol Sciences	Broadband Antenna	JB1	A040904-1	2007-08-14	2008-08-14
Giga-tronics	Signal Generator	1026	270801	2007-09-29	2008-09-29
Sunol Sciences	Horn Antenna	DRH-118	A052604	2007-09-25	2008-09-25
Brüel & Kjær	Ear Simulator	4185	2190351	2008-05-30	2009-05-30
Brüel & Kjær	Telephone Test Head	4602B	2174439	2008-05-30	2009-05-30
LISTEN, Inc.	Microphone Power Supply	N/A	1199-PS165	2008-05-30	2009-05-30
Brüel & Kjær	Measuring Amplifier	2610	SA0252	2008-05-30	2009-05-30

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attests that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

Test System Setup



Test Standard

ETSI EN 301 489-1 V1.6.1 / EN 61000-4-3: 2006

Test Level 2 at 3V / m

Test Levels and Performance Criterion

Test Level

Level	Field Strength (V/m)
1.	1
2.	3
3.	10
X.	Special

Performance Criterion: A* (*Note: “A” stand for, the speech output signal level shall be at least 35 dB less than the reference level recorded before the start of the test. This shall be verified by the procedure in EN 301 489-6 V1.2.1 clause 5.3.2.)

Test Procedure

The EUT and its simulators are placed on a turn table which is 0.8 meter above the ground. The EUT is set 3 meters away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarizations of the antenna are set on test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually.

In order to judge the EUT performance, a CCD camera is used to monitor the EUT.

All the scanning conditions are as follows:

Condition of Test	Remarks
-----	-----
1. Field Strength	3 V/m (Test Level 2)
2. Radiated Signal	Modulated
3. Scanning Frequency	80 - 1000 MHz and 1400-2000MHz
4. Sweeping time of radiated	0.0015 decade/s
5. Dwell Time	1 Sec.

Test Data and Setup Photo**Environmental Conditions**

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Bruce Zhang on 2008-06-19.

Test Mode: Talking

Frequency Range (MHz)	Front (3 V/m)		Rear (3 V/m)		Left Side (3 V/m)		Right Side (3 V/m)	
	VERT	HORI	VERT	HORI	VERT	HORI	VERT	HORI
80-1000	A	A	A	A	A	A	A	A
1400-2000	A	A	A	A	A	A	A	A



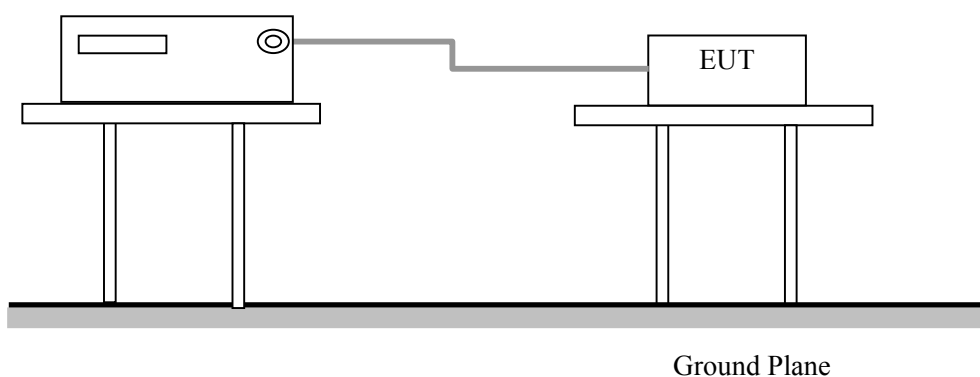
Test Setup photos

ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - FAST TRANSIENT IMMUNITY COMMON MODE

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-M	303279	2008-03-25	2009-03-25
EM Test	Auto-transformer	MV2616	0403-16	2008-03-25	2009-03-25

Test System Setup



Test Standard

ETSI EN 301 489-1 V1.6.1/EN 61000-4-4: 2004
Test level 2 at 1 kV

Test Level

Open Circuit Output Test Voltage $\pm 10\%$		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1	0.5 kV	0.25 kV
2	1 kV	0.5 kV
3	2 kV	1 kV
4	4 kV	2 kV
X	Special	Special

Performance Criterion: B

Test Procedure

The EUT was arranged for Power Line Coupling and for I/O Line Coupling through a capacitive clamp, where applicable. (Note: The I/O coupling test using a capacitive clamp is performed on the I/O interface cables that are longer in length than 3 meters.) A metal ground plane 2.4 meter by 2.0 meter was placed between the floor and the table and is connected to the earth by a 2.0 meter ground rod. The ground rod is connected to the test facility's electrical earth.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Karo Liao on 2008-06-18.

Test Mode: Talking

EN 61000-4-4 Test Points		Test Levels (kV)							
		+0.5	-0.5	+1.0	-1.0	+2.0	-2.0	+4.0	-4.0
AC mains Power input ports	L1	A	A	A	A	/	/	/	/
	L2	A	A	A	A	/	/	/	/
	Earth	/	/	/	/	/	/	/	/
	L1+L2	A	A	A	A	/	/	/	/
	L1 + Earth	/	/	/	/	/	/	/	/
	L2 + Earth	/	/	/	/	/	/	/	/
	L1+L2+Earth	/	/	/	/	/	/	/	/
Signal Port	RJ11	A	A	/	/	/	/	/	/



RJ11 Port:



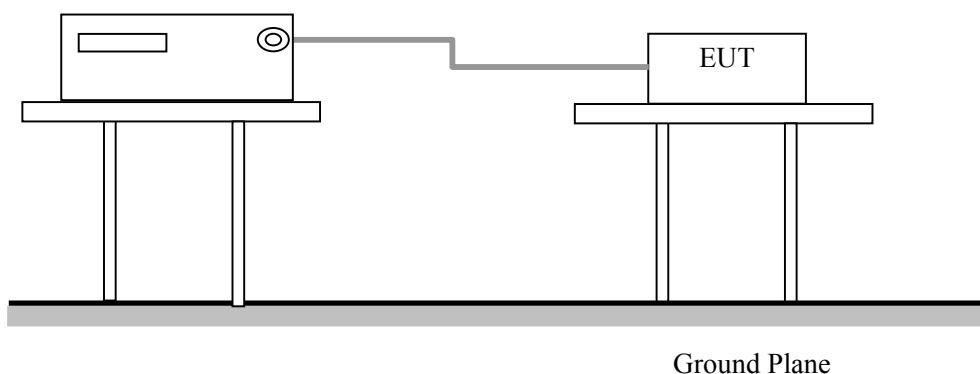
Test Setup photo

ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - SURGES, COMMON AND DIFFERENTIAL MODE

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-M	303279	2008-03-26	2009-03-26
EM Test	Auto-transformer	MV2616	0403-16	2007-09-29	2008-09-29

Test System Setup



Test Standard

ETSI EN 301 489-1 V1.6.1 / EN 61000-4-5: 2006
L-N: Test level 2 at 1 kV

Test Level

Open Circuit Output Test Voltage $\pm 10\%$		
Level	On Power Supply Lines	On I/O (Input/Output) Signal data and control lines
1	0.5 kV	0.25 kV
2	1 kV	0.5 kV
3	2 kV	1 kV
4	4 kV	2 kV
X	Special	Special

Performance Criterion: B

Test Procedure

- 1) For line to line coupling mode, provide a 0.5 kV 1.2/50us voltage surge (at open-circuit condition).
- 2) At least 5 positive and 5 negative (polarity) tests with a maximum 1/min repetition rate are conducted during test.
- 3) Different phase angles are done individually.
- 4) Record the EUT operating situation during compliance test and decide the EUT immunity criterion for above each test.

Test Data and Setup Photo**Environmental Conditions**

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Karo Liao on 2008-06-18.

Test Mode: Talking(AC Mains)

Level	Voltage	Poll	Path	Pass	Fail
1	0.5 kV	±	L-N	A	/
2	1 kV	±	L-N	A	/
3	2 kV	±	L-N, L-PE, N-PE	/	/
4	4 kV	±	L-N, L-PE, N-PE	/	/

Test Mode: Talking (RJ11 Port)

Level	Voltage	Poll	Path	Pass	Fail
1	0.5 kV	±	Line-Line	A	/

AC Mains



RJ11 Port:



Test Setup photo

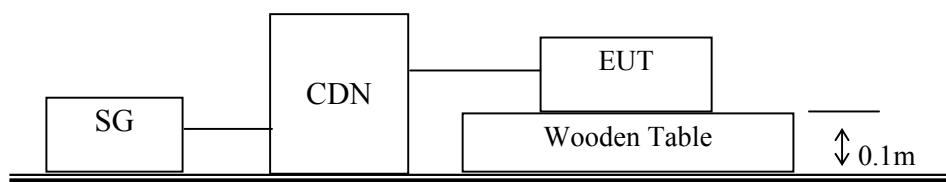
ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - RF COMMON MODE, 0.15 MHz to 80 MHz)

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM	CDN	M3	303288	2008-03-25	2009-03-25
EM Test	C/S Tester	CWS500	303277	2008-03-25	2009-03-25
EM Test	Attenuator	6dB	303282	2007-11-15	2008-11-15
EM Test	Attenuator	6dB	303283	N/A	N/A
FCC	Bulk Current Injection Probe	F-120-9A	303284	2008-03-25	2009-03-25
Brüel & Kjær	Ear Simulator	4185	2190351	2008-05-30	2009-05-30
Brüel & Kjær	Telephone Test Head	4602B	2174439	2008-05-30	2009-05-30
LISTEN, Inc.	Microphone Power Supply	N/A	1199-PS165	2008-05-30	2009-05-30
Brüel & Kjær	Measuring Amplifier	2610	SA0252	2008-05-30	2009-05-30
SCHAFFNER	CDN	CDN T200	16891	2007-10-16	2008-10-16

* **Statement of Traceability:** Bay Area Compliance Laboratories Corp. (Shenzhen) attested that all calibrations have been performed in accordance to NVLAP requirements, traceable to the NIST.

Test Setup



Test Standard

ETSI EN 301 489-1 V1.6.1/EN 61000-4-6: 2006
Test level 2 at 3 V (r.m.s.), 0.15 MHz ~ 80 MHz,

Test Level

Level	Voltage Level (r.m.s.) (V)
1	1
2	3
3	10
X	Special

Performance Criterion: A* (*Note: “A” stand for, the speech output signal level shall be at least 35 dB less than the reference level recorded before the start of the test. This shall be verified by the procedure in EN 301 489-6 V1.2.1 clause 5.3.2.)

Test Procedure

- 1) Let the EUT work in test mode and test it.
- 2) The EUT are placed on an insulating support 0.1 m high above a ground reference plane. CDN (coupling and decoupling device) is placed on the ground plane about 0.3 m from EUT. Cables between CDN and EUT are as short as possible, and their height above the ground reference plane shall be between 30 and 50 mm (where possible).
- 3) The disturbance signal described below is injected to EUT through CDN.
- 4) The EUT operates within its operational mode(s) under intended climatic conditions after power on.
- 5) The frequency range is swept from 150 kHz to 80 MHz using 3V signal level, and with the disturbance signal 80% amplitude modulated with a 1 kHz sine wave.
- 6) The rate of sweep shall not exceed 1.5×10^{-3} decades/s. Where the frequency is swept incrementally, the step size shall not exceed 1% of the start and thereafter 1% of the preceding frequency value.
- 7) Recording the EUT operating situation during compliance testing and decide the EUT immunity criterion.

Test Data and Setup Photo

Environmental Conditions

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Bruce Zhang on 2008-06-19.

Test Mode: Talking

Table 1: AC mains power input port
Frequency range: 150 kHz to 80 MHz
Modulation: Amplitude 80%, 1 kHz sinewave
Test level: 3V r.m.s.

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
1	1	/	/
2	3	A	/
3	10	/	/
X	Special	/	/

Test Mode: Talking (RJ11 Port)

Level	Voltage Level (r.m.s.) U_0	Pass	Fail
2	3	A	/

AC Mains



RJ11 Port:



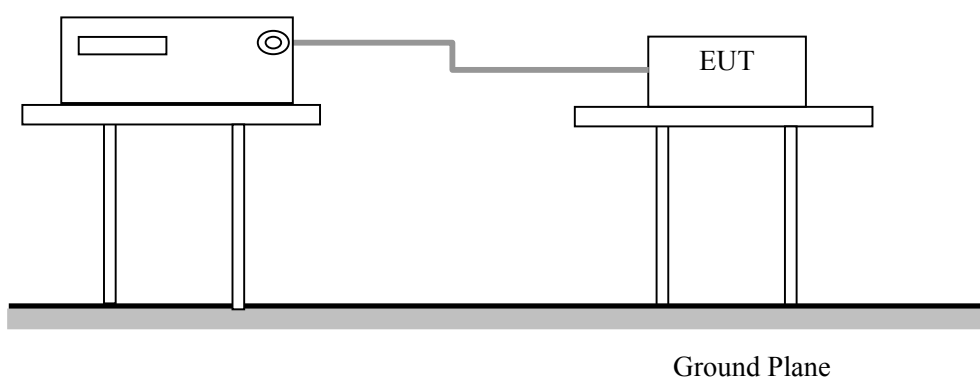
Test Setup photo

ETSI EN 301 489-6 V1.2.1 (2002-08) §7.2 - VOLTAGE DIPS AND INTERRUPTIONS

Test Equipment

Manufacturer	Description	Model	Serial Number	Calibration Date	Calibration Due Date
EM Test	Ultra Compact Generator	UCS500-M	303279	2008-03-26	2009-03-26
EM Test	Auto-transformer	MV2616	0403-16	2007-09-29	2008-09-29

Test System Setup



Test Standard

ETSI EN 301 489-1 V1.6.1/EN 61000-4-11: 2004
Test levels and Performance Criterion

Test Level

Test Level	Voltage dip and short interruptions %UT	TD (ms)
1	30	10
2	60	100
3	>95	5000

Performance Criterion: C & B

Test Procedure

- 1) The interruption is introduced at selected phase angles with specified duration.
- 2) Record any degradation of performance.

Test Data and Setup Photo**Environmental Conditions**

Temperature:	25 ° C
Relative Humidity:	56 %
ATM Pressure:	100.0 kPa

The testing was performed by Karo Liao on 2008-06-18.

Test Mode: Talking

Level	U2	Td (ms)	Phase Angle	N	Pass	Fail
1	30%	10	0/90/180/270	3	A	/
2	60%	100	0/90/180/270	3	B	/
3	>95%	5000	0/90/180/270	3	C	/



Test Setup photo

EXHIBIT A - EUT PHOTOGRAPHS

Full View



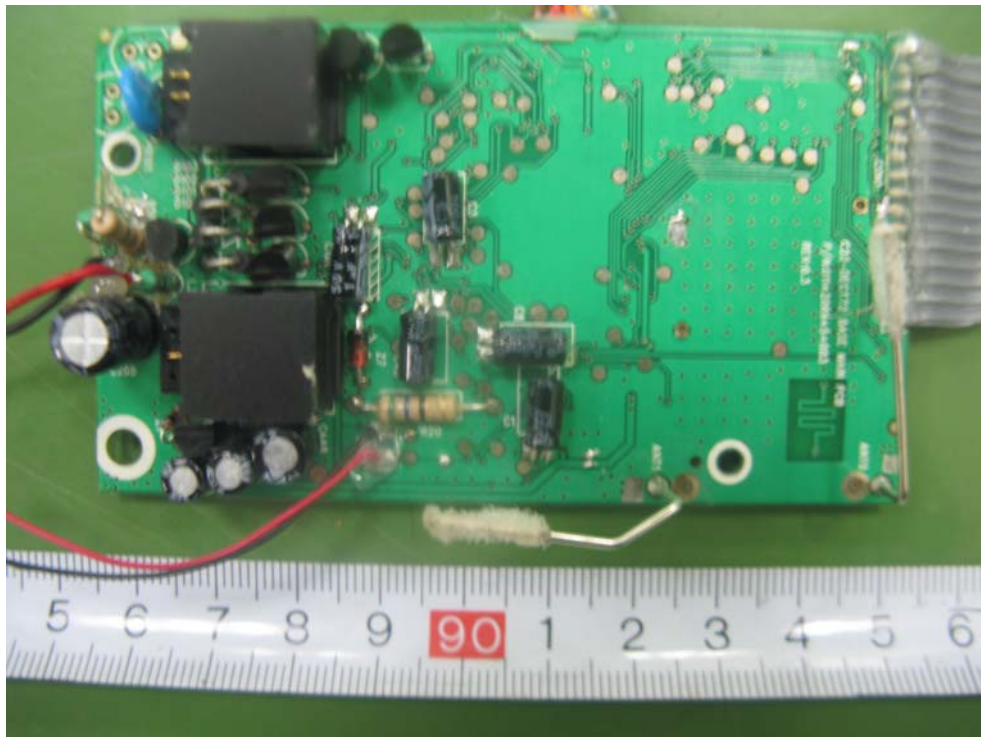
EUT - Top View



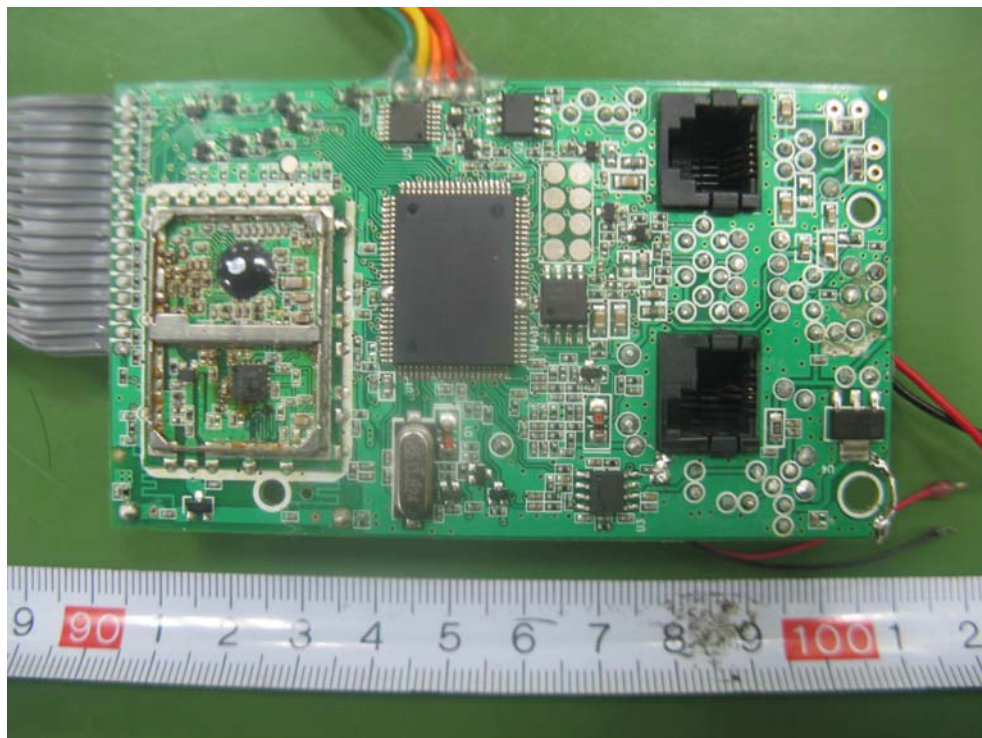
[illegible]

The image displays the internal components of a Sony CCD camera, laid out on a green surface. On the left is the black plastic camera housing with the lens assembly and a circular sensor cover. On the right is the white plastic housing containing the green printed circuit board (PCB) with various electronic components, including a large black rectangular sensor chip. A multi-colored ribbon cable connects the sensor to a separate yellow PCB at the bottom, which features a small digital display and several buttons. A ruler is positioned at the bottom of the frame for scale.

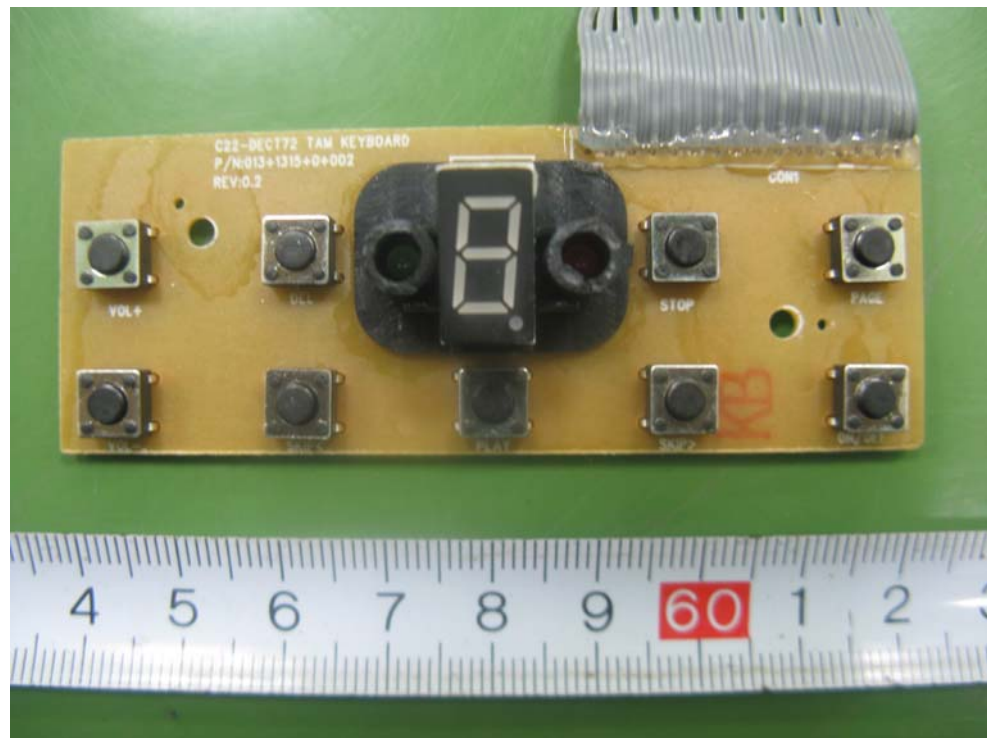
EUT - Main Board Top Components View



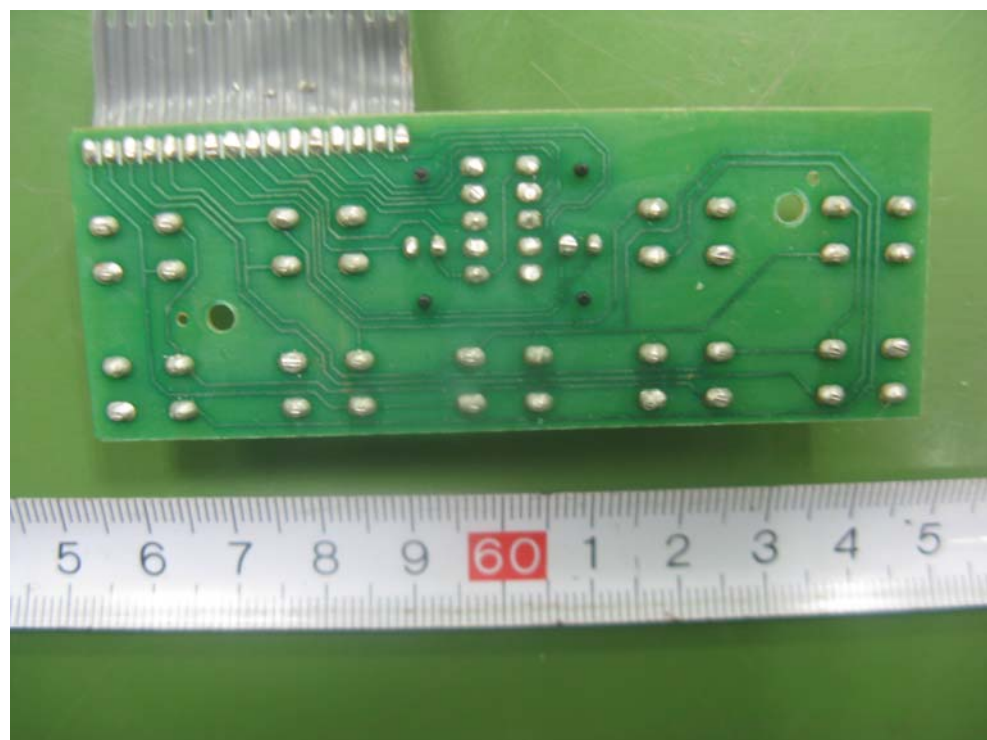
EUT - Main Board Bottom Components View



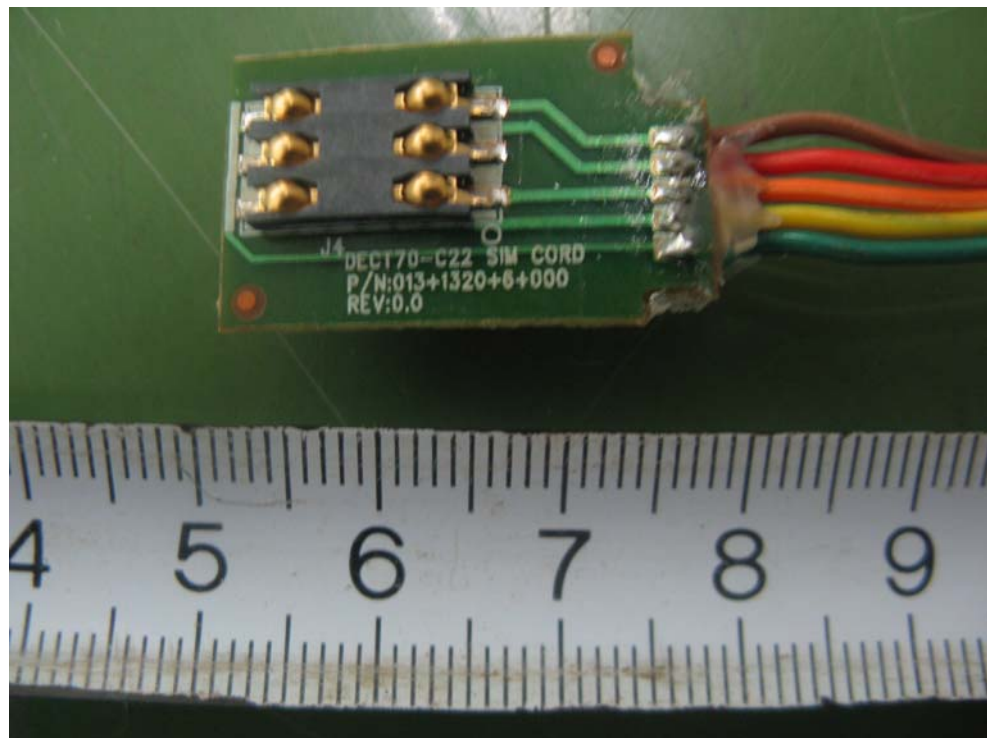
EUT - Key Board Top Components View



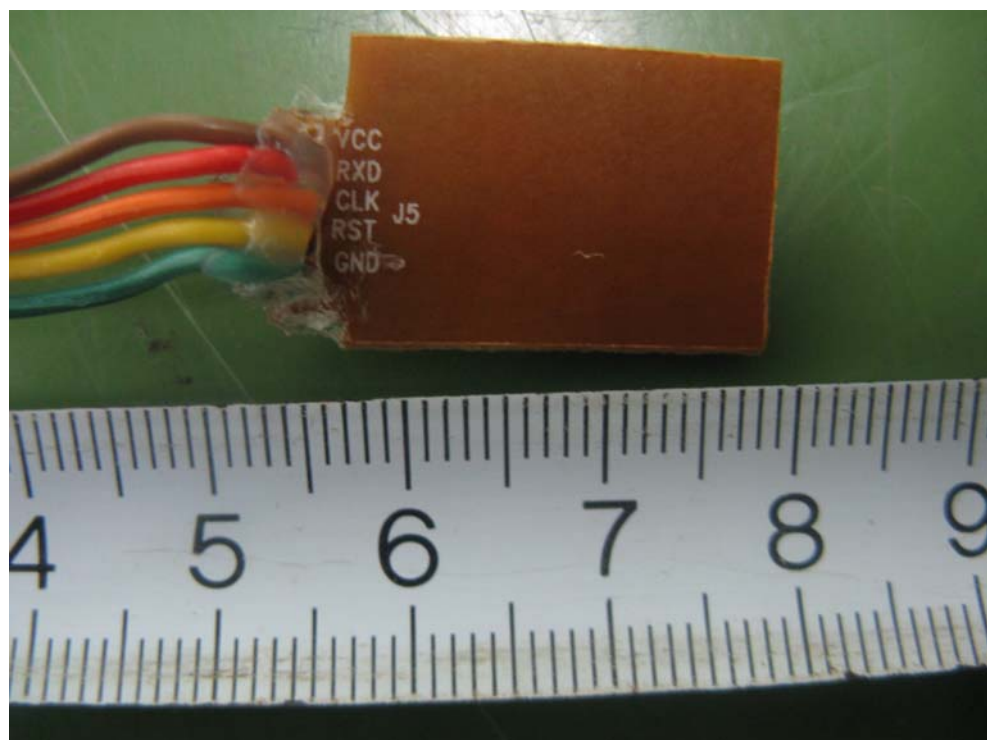
EUT - Key Board Bottom Components View



EUT – SIM Card Board Top Components View



EUT - SIM Card Board Bottom Components View



AC/DC Adapter View

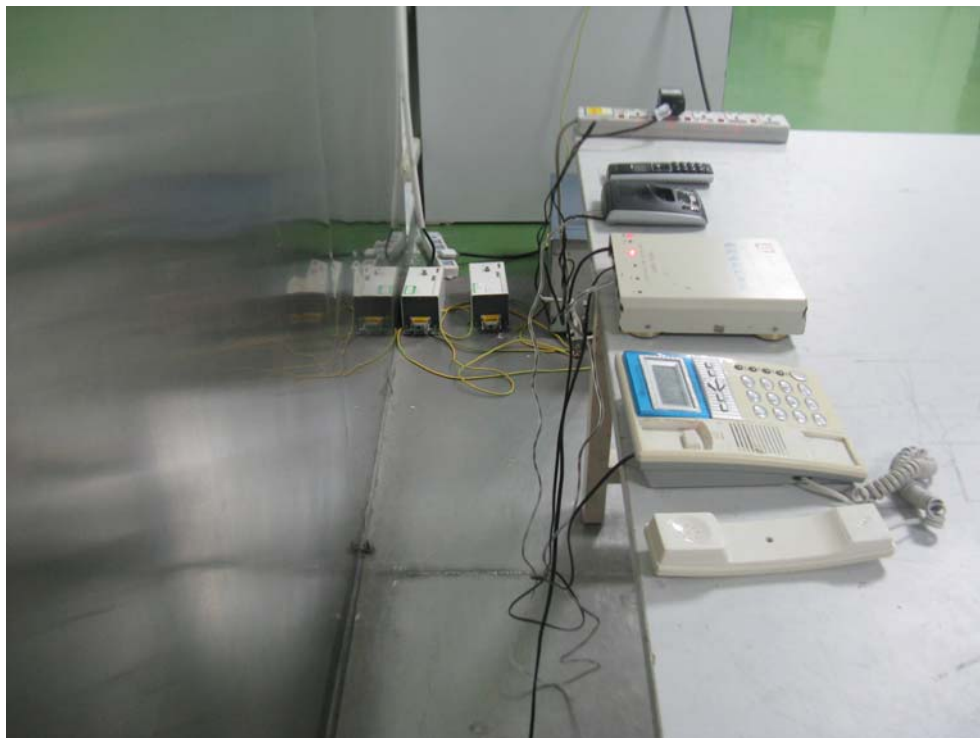


EXHIBIT B – TEST SETUP PHOTOGRAPHS

Conducted Emissions - Front View (AC Port)



Conducted Emissions - Side View (AC Port)



Conducted Emissions - Front View (RJ11 Port)



Conducted Emissions - Side View (RJ11 Port)



Radiated Emissions - Front View



Radiated Emissions - Rear View



******* END OF REPORT *******